



Title of Change:	HDG4/ HDG4D 1.2um BCDMOS Cross Qualification from Bucheon, Korea 6" to S. Portland Maine 8".	
Proposed first ship date:	29 January 2019	
Contact information:	Contact your local ON Semiconductor Sales Office or <Taehwan.Lee@onsemi.com>	
Samples:	Contact your local ON Semiconductor Sales Office or <PCN.samples@onsemi.com> Sample requests are to be submitted no later than 30 days from the date of first notification, Initial PCN or Final PCN, for this change.	
Additional Reliability Data:	Contact your local ON Semiconductor Sales Office or <Jacob.Saliba@onsemi.com>	
Type of notification:	This is a Final Product/Process Change Notification (FPCN) sent to customers. FPCNs are issued 90 days prior to implementation of the change. ON Semiconductor will consider this change accepted, unless an inquiry is made in writing within 30 days of delivery of this notice. To do so, contact <PCN.Support@onsemi.com>	
Change Part Identification:	As material from different FABs cannot be combined into (1) reel, product from Maine will show CS: US (Custom Source) on the label of the reel and box. Please see sample MPN on Page 2 at the following URL http://www.onsemi.com/pub/Collateral/LABELRM-D.PDF to see the location of the CS Identifier.	
Change Category:	<input checked="" type="checkbox"/> Wafer Fab Change <input type="checkbox"/> Assembly Change <input type="checkbox"/> Test Change <input type="checkbox"/> Other _____	
Change Sub-Category(s):	<input checked="" type="checkbox"/> Manufacturing Site Addition <input type="checkbox"/> Material Change <input type="checkbox"/> Datasheet/Product Doc change <input type="checkbox"/> Manufacturing Site Transfer <input type="checkbox"/> Product specific change <input type="checkbox"/> Shipping/Packaging/Marking <input type="checkbox"/> Manufacturing Process Change <input type="checkbox"/> Other: _____	
Sites Affected:	ON Semiconductor Sites: ON S. Portland, Maine	External Foundry/Subcon Sites: None
Description and Purpose:		
The purpose of this project is to expand Front-End wafer fabrication capacity and supply flexibility by the cross qualification of ON Bucheon Korea's (1.2um BCDMOS) 6 inch HDG4/ HDG4D fab process into ON S. Portland, Maine's 8 inch fab site.		
	Before Change Description	After Change Description
Fab Sites Qualified for HDG4D	ON Bucheon Korea – 6 inch Fab Site	ON Bucheon, Korea – 6 inch Fab Site ON S. Portland, Maine – 8 inch Fab Site



Reliability Data Summary:

QV DEVICE NAME: FAN73894MX

PACKAGE: SOICW28

Test	Specification	Condition	Interval	Results
HTOL	JESD22-A108	Ta=125°C, 100 % max rated Vcc	1008 hrs	0/231
HTSL	JESD22-A103	Ta= 150°C	1008 hrs	0/231
TC-PC	JESD22-A104	Ta= -55°C to +150°C	500 cyc	0/231
HAST-PC	JESD22-A110	110°C, 85% RH, 18.8psig, 100V bias	264 hrs	0/231
uHAST-PC	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs	0/231
PC	J-STD-020 JESD-A113	MSL 3 @ 260 °C		0/693
RSH	JESD22- B106	Ta = 265C, 10 sec		0/40

QV DEVICE NAME: FSFR2100XS

PACKAGE: SIP9

Test	Specification	Condition	Interval	Results
HTOL	JESD22-A108	Ta=83°C, Tjmax=120C, 100 % max rated Vcc	1008 hrs	0/231
HTSL	JESD22-A103	Ta= 150°C	1008 hrs	0/231
TC	JESD22-A104	Ta= -55°C to +150°C	500 cyc	0/231
HAST	JESD22-A110	110°C, 85% RH, 18.8psig, 100V bias	628 hrs	0/231
uHAST	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs	0/231
RSH	JESD22- B106	Ta = 265C, 10 sec		0/40

Estimated date for qualification completion: **2 November 2018**

Electrical Characteristic Summary: Electrical characteristics are not impacted.

List of Affected Parts:

Part Number	Qualification Vehicle
FAN73892MX	FAN73894MX
FAN73893MX	FAN73894MX
FAN7389MX1	FAN73894MX
FAN73894MX	FAN73894MX
FSFR2100XS	FSFR2100XS
FSFR2100XSL	FSFR2100XS
FLS2100XS	FSFR2100XS
FAN7888MX	FAN73894MX
FAN7711MX	FAN73894MX
FAN7388MX	FAN73894MX
FAN7383MX	FAN73894MX

Japanese translation of the notification starts here.
通知の日本語訳はここから始まります。

Note: The Japanese version is for reference only. In case of any differences between the English and Japanese version, the English version shall control.

注：日本語版は参照用です。英語版と日本語版の違いがある場合は、英語版が優先されます。



信頼性データの要約:

QV 素子名: FAN73894MX

パッケージ: SOICW28

テスト	仕様	条件	間隔	結果
HTOL	JESD22-A108	Ta=125°C, 100 % max rated Vcc	1008 hrs	0/231
HTSL	JESD22-A103	Ta= 150°C	1008 hrs	0/231
TC-PC	JESD22-A104	Ta= -55°C to +150°C	500 cyc	0/231
HAST-PC	JESD22-A110	110°C, 85% RH, 18.8psig, 100V bias	264 hrs	0/231
uHAST-PC	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs	0/231
PC	J-STD-020 JESD-A113	MSL 3 @ 260 °C		0/693
RSH	JESD22- B106	Ta = 265C, 10 sec		0/40

QV 素子名: FSFR2100XS

パッケージ: SIP9

テスト	仕様	条件	間隔	結果
HTOL	JESD22-A108	Ta=83°C, Tjmax=120C, 100 % max rated Vcc	1008 hrs	0/231
HTSL	JESD22-A103	Ta= 150°C	1008 hrs	0/231
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HAST	JESD22-A110	110°C, 85% RH, 18.8psig, 100V bias	628 hrs	0/231
uHAST	JESD22-A118	130°C, 85% RH, 18.8psig, unbiased	96 hrs	0/231
RSH	JESD22- B106	Ta = 265C, 10 sec		0/40

認定完了予定日: 2018年11月2日

電気的特性の要約: 電気的特性への影響はありません。

影響を受ける部品の一覧:

部品番号	品質試験用ピークル
FAN73892MX	FAN73894MX
FAN73893MX	FAN73894MX
FAN7389MX1	FAN73894MX
FAN73894MX	FAN73894MX
FSFR2100XS	FSFR2100XS
FSFR2100XSL	FSFR2100XS
FLS2100XS	FSFR2100XS
FAN7888MX	FAN73894MX
FAN7711MX	FAN73894MX
FAN7388MX	FAN73894MX
FAN7383MX	FAN73894MX



Appendix A: Changed Products

Product	Customer Part Number	Qualification Vehicle
FAN7383MX		FAN73894MX
FAN7388MX		FAN73894MX
FAN73892MX		FAN73894MX
FAN73893MX		FAN73894MX
FAN73894MX		FAN73894MX
FAN7389MX1		FAN73894MX
FAN7711MX		FAN73894MX
FAN7888MX		FAN73894MX
FLS2100XS		FSFR2100XS
FSFR2100XS		FSFR2100XS
FSFR2100XSL		FSFR2100XS